Applicant(s)/Patent Under Application/Control No. Reexamination 10/789,390 CROWLEY, ROBERT JOSEPH Notice of References Cited Examiner **Art Unit** Page 1 of 1 2874 John D. Lee, U.S. PATENT DOCUMENTS **Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY 03-2000 US-6,038,060 Crowley, Robert Joseph 359/328 Α * US-6,258,401 07-2001 427/126.3 Crowley, Robert Joseph В * 12-2003 U.S-6,669,256 294/99.1 С Nakayama et al. 03-2004 US-6,700,550 Crowley, Robert Joseph 343/792.5 D * E US-6,802,549 10-2004 Nakayama et al. 294/99.1 F US-6,805,390 10-2004 Nakayama et al. 294/99.1 US-G Н US-US-US-USκ US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) Poncharal et al, "Electrostatic Deflections and Electromechanical Resonances of Carbon Nanotubes", SCIENCE, vol. 283, 05 U March 1999, pages 1513-1516.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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